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^{*} Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. Department of Commerce (REV. 2-82) Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Atty. Docket No. 070180.0141 (A33828 PCT USA) Applicant: Fuhr et al.	Serial No. 09/720,275
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13M	*	4	7	2	6	9	0	4	02/23/88	Ayers	210	658	
BIM	*	4	7	6	4	4	7	3	08/16/88	Matschke et al.	435	287	
BUM	*	4	8	0	4	3	5	5	02/14/89	Brimhall et al.	494	20	
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